



Plot 7-629. Band Edge Emission Plot
(B66_15M+10M+10M_QPSK, Port 2)



Plot 7-630. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_QPSK, Port 2)



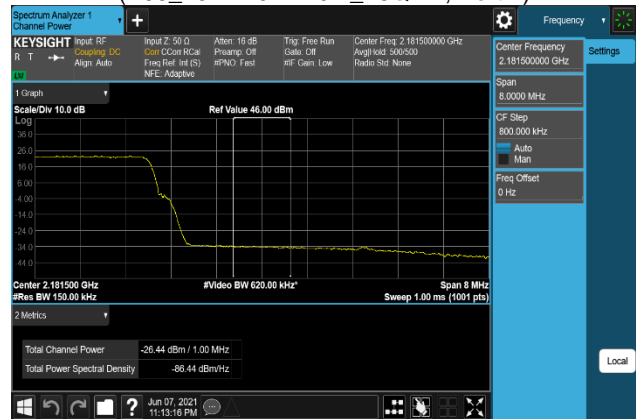
Plot 7-631. Band Edge Emission Plot
(B66_15M+10M+10M_16QAM, Port 2)



Plot 7-632. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_16QAM, Port 2)



Plot 7-633. Band Edge Emission Plot
(B66_15M+10M+10M_64QAM, Port 2)



Plot 7-634. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_64QAM, Port 2)

FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
Test Report S/N: 8K21053101R1.A3L	Test Dates: 06/01/2021-06/15/2021	EUT Type: RRU(RF4402d)		Page 143 of 515



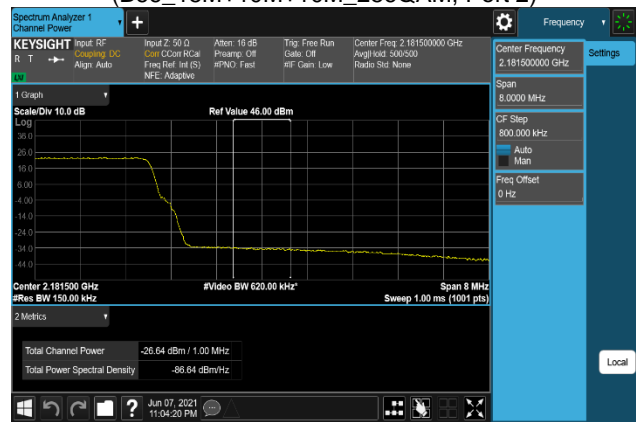
Plot 7-635. Band Edge Emission Plot
(B66_15M+10M+10M_256QAM, Port 2)



Plot 7-636. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_256QAM, Port 2)



Plot 7-637. Band Edge Emission Plot
(B66_15M+10M+10M_QPSK, Port 3)



Plot 7-638. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_QPSK, Port 3)



Plot 7-639. Band Edge Emission Plot
(B66_15M+10M+10M_16QAM, Port 3)



Plot 7-640. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_16QAM, Port 3)

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Test Report S/N: 8K21053101R1.A3L	Test Dates: 06/01/2021-06/15/2021	EUT Type: RRU(RF4402d)		Page 144 of 515



Plot 7-641. Band Edge Emission Plot
(B66_15M+10M+10M_64QAM, Port 3)



Plot 7-642. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_64QAM, Port 3)



Plot 7-643. Band Edge Emission Plot
(B66_15M+10M+10M_256QAM, Port 3)





Plot 7-644. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_256QAM, Port 3)

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Test Report S/N: 8K21053101R1.A3L	Test Dates: 06/01/2021-06/15/2021	EUT Type: RRU(RF4402d)		Page 145 of 515

- B66_20M+5M+10M_Contiguous

Channel	Port	Measured Range (MHz)	Max. Value (dBm)				Limit (dBm)
			QPSK	16QAM	64QAM	256QAM	
Low	0	2109 to 2110	-27.028	-26.346	-26.601	-26.656	-19
	0	2108 to 2109	-40.510	-40.730	-40.020	-40.170	-19
	1	2109 to 2110	-26.768	-26.290	-26.905	-25.986	-19
	1	2108 to 2109	-40.160	-40.610	-39.900	-39.990	-19
	2	2109 to 2110	-27.774	-27.626	-27.816	-27.507	-19
	2	2108 to 2109	-41.810	-41.840	-41.980	-41.820	-19
	3	2109 to 2110	-26.403	-27.205	-27.700	-27.856	-19
	3	2108 to 2109	-41.880	-41.910	-41.840	-41.800	-19
High	0	2180 to 2181	-21.654	-21.765	-20.935	-21.272	-19
	0	2181 to 2182	-28.060	-27.460	-27.400	-27.480	-19
	1	2180 to 2181	-21.639	-21.961	-21.515	-21.513	-19
	1	2181 to 2182	-27.480	-27.490	-27.510	-27.640	-19
	2	2180 to 2181	-22.147	-21.770	-22.683	-21.962	-19
	2	2181 to 2182	-28.130	-27.410	-27.820	-27.570	-19
	3	2180 to 2181	-21.477	-21.698	-22.166	-21.888	-19
	3	2181 to 2182	-28.050	-28.190	-28.140	-28.120	-19



Table 7-31. Band Edge Emission Summary Data (B66_20M+5M+10M_Contiguous)

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Test Report S/N: 8K21053101R1.A3L	Test Dates: 06/01/2021-06/15/2021	EUT Type: RRU(RF4402d)		Page 146 of 515	

- B66_20M+5M+10M_Non-Contiguous

Edge	Port	Measured Freq. (MHz)	Max. Value (dBm)				Limit (dBm)
			QPSK	16QAM	64QAM	256QAM	
Lower	0	2109 to 2110	-24.141	-24.022	-25.188	-24.372	-19
	0	2108 to 2109	-38.600	-39.380	-39.780	-39.490	-19
	1	2109 to 2110	-24.113	-23.684	-24.494	-24.870	-19
	1	2108 to 2109	-38.960	-39.070	-39.090	-39.230	-19
	2	2109 to 2110	-25.261	-25.404	-26.091	-25.179	-19
	2	2108 to 2109	-40.530	-40.470	-40.600	-41.210	-19
	3	2109 to 2110	-24.159	-23.533	-24.628	-25.026	-19
	3	2108 to 2109	-40.910	-40.980	-41.520	-41.240	-19
Upper	0	2180 to 2181	-21.539	-21.138	-20.631	-23.427	-19
	0	2181 to 2182	-26.280	-26.560	-26.450	-26.590	-19
	1	2180 to 2181	-20.649	-21.167	-21.398	-20.399	-19
	1	2181 to 2182	-26.290	-26.240	-26.270	-26.170	-19
	2	2180 to 2181	-20.696	-20.817	-22.472	-22.232	-19
	2	2181 to 2182	-26.760	-27.110	-26.740	-27.200	-19
	3	2180 to 2181	-21.227	-22.839	-21.303	-22.317	-19
	3	2181 to 2182	-28.630	-28.740	-27.070	-27.170	-19

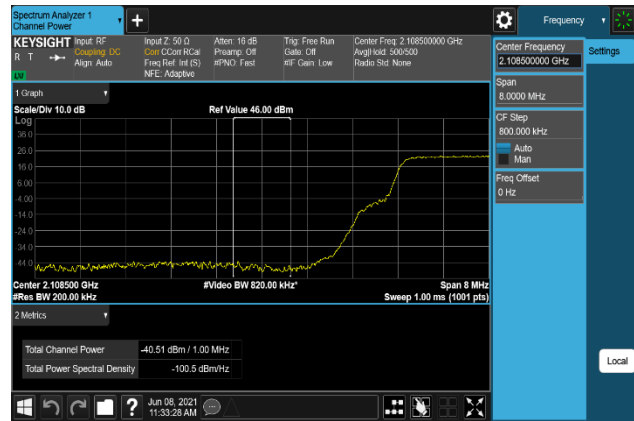
Table 7-32. Band Edge Emission Summary Data (B66_20M+5M+10M_Non-Contiguous)

FCC ID: A3LRF4402D-D1A		MEASUREMENT REPORT (Class II Permissive Change)			Approved by: Technical Manager
Test Report S/N: 8K21053101R1.A3L	Test Dates: 06/01/2021-06/15/2021	EUT Type: RRU(RF4402d)		Page 147 of 515	

- B66_20M+5M+10M_Contiguous



Plot 7-645. Band Edge Emission Plot
(B66_20M+5M+10M_QPSK - Low Channel, Port 0)



Plot 7-646. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_QPSK - Low Channel, Port 0)



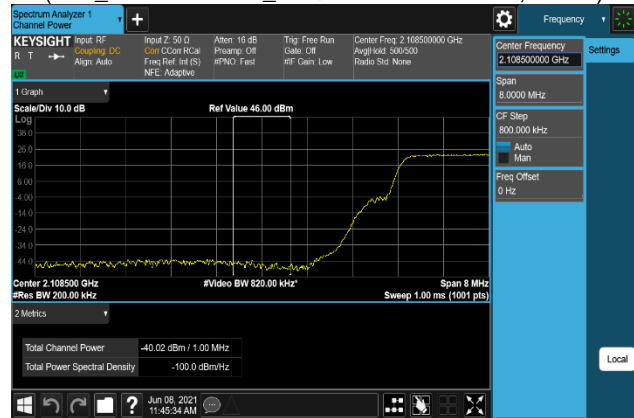
Plot 7-647. Band Edge Emission Plot
(B66_20M+5M+10M_16QAM - Low Channel, Port 0)



Plot 7-648. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_16QAM - Low Channel, Port 0)



Plot 7-649. Band Edge Emission Plot
(B66_20M+5M+10M_64QAM - Low Channel, Port 0)

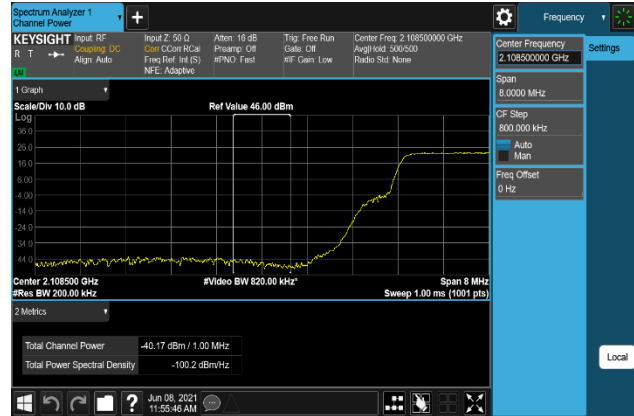


Plot 7-650. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_64QAM - Low Channel, Port 0)

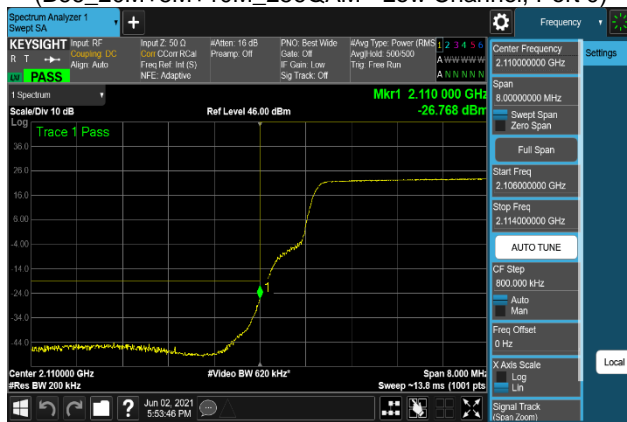
FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
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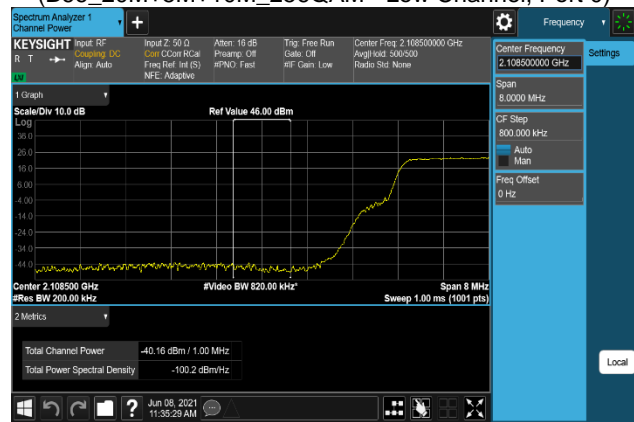
Plot 7-651. Band Edge Emission Plot
(B66_20M+5M+10M_256QAM - Low Channel, Port 0)



Plot 7-652. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_256QAM - Low Channel, Port 0)



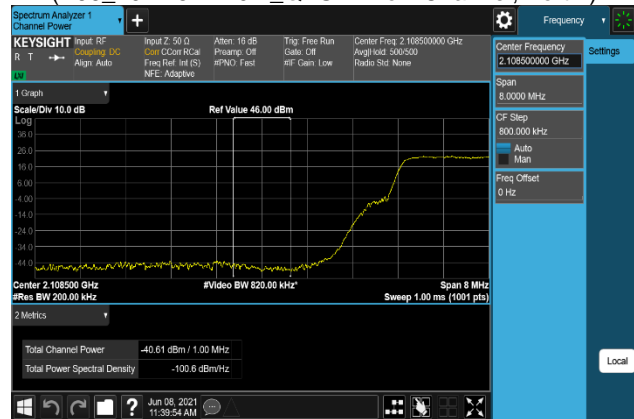
Plot 7-653. Band Edge Emission Plot
(B66_20M+5M+10M_QPSK - Low Channel, Port 1)



Plot 7-654. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_QPSK - Low Channel, Port 1)



Plot 7-655. Band Edge Emission Plot
(B66_20M+5M+10M_16QAM - Low Channel, Port 1)

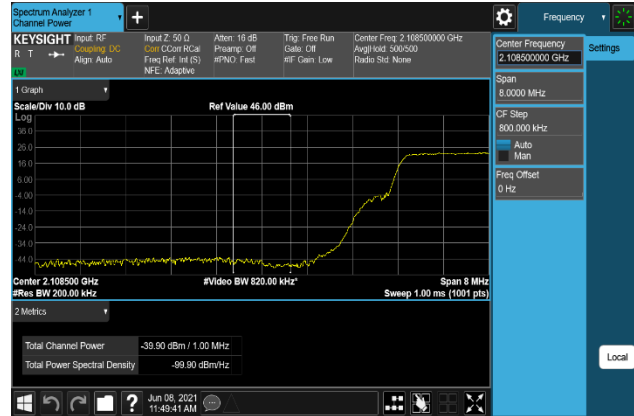


Plot 7-656. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_16QAM - Low Channel, Port 1)

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Test Report S/N: 8K21053101R1.A3L	Test Dates: 06/01/2021-06/15/2021	EUT Type: RRU(RF4402d)		Page 149 of 515



Plot 7-657. Band Edge Emission Plot
(B66_20M+5M+10M_64QAM - Low Channel, Port 1)



Plot 7-658. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_64QAM - Low Channel, Port 1)



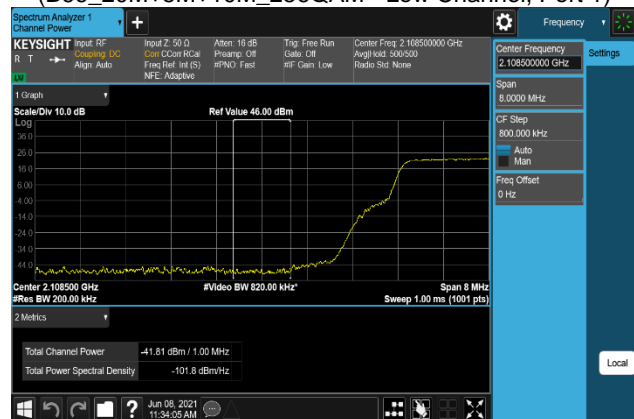
Plot 7-659. Band Edge Emission Plot
(B66_20M+5M+10M_256QAM - Low Channel, Port 1)



Plot 7-660. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_256QAM - Low Channel, Port 1)

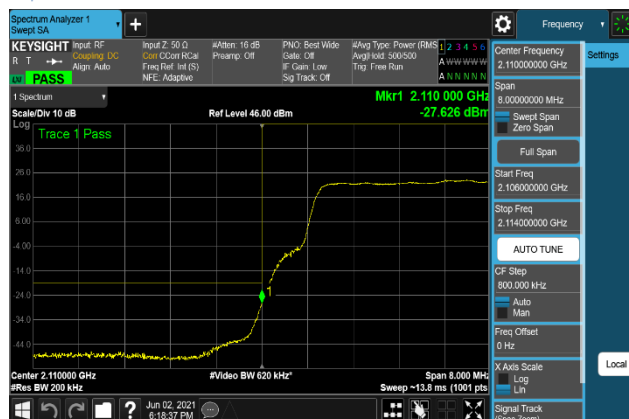


Plot 7-661. Band Edge Emission Plot
(B66_20M+5M+10M_QPSK - Low Channel, Port 2)

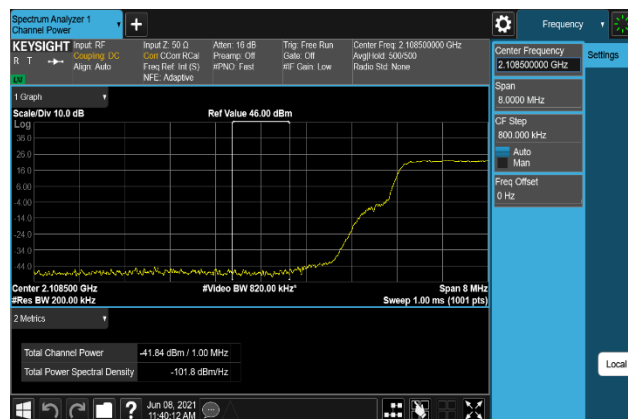


Plot 7-662. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_QPSK - Low Channel, Port 2)

FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
Test Report S/N: 8K21053101R1.A3L	Test Dates: 06/01/2021-06/15/2021	EUT Type: RRU(RF4402d)		Page 150 of 515



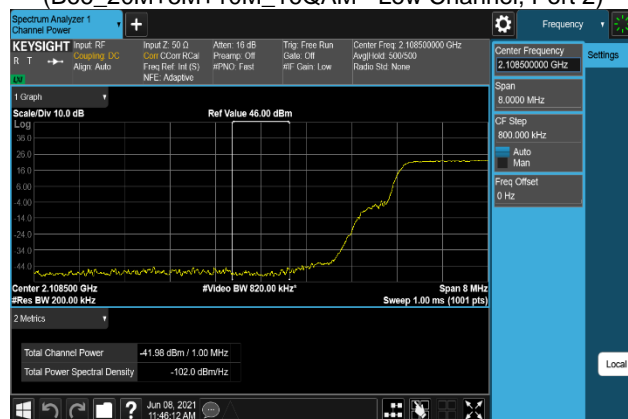
Plot 7-663. Band Edge Emission Plot
(B66_20M+5M+10M_16QAM - Low Channel, Port 2)



Plot 7-664. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_16QAM - Low Channel, Port 2)



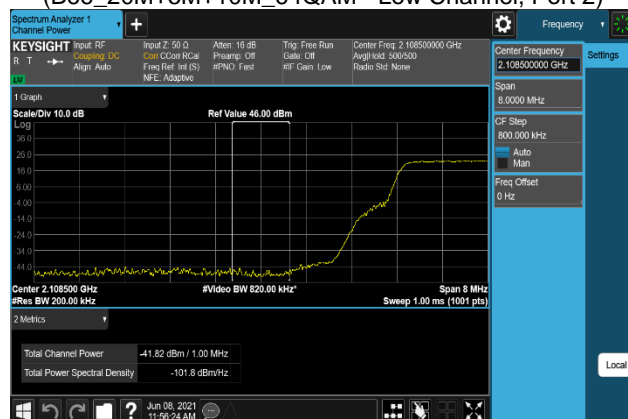
Plot 7-665. Band Edge Emission Plot
(B66_20M+5M+10M_64QAM - Low Channel, Port 2)



Plot 7-666. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_64QAM - Low Channel, Port 2)



Plot 7-667. Band Edge Emission Plot
(B66_20M+5M+10M_256QAM - Low Channel, Port 2)

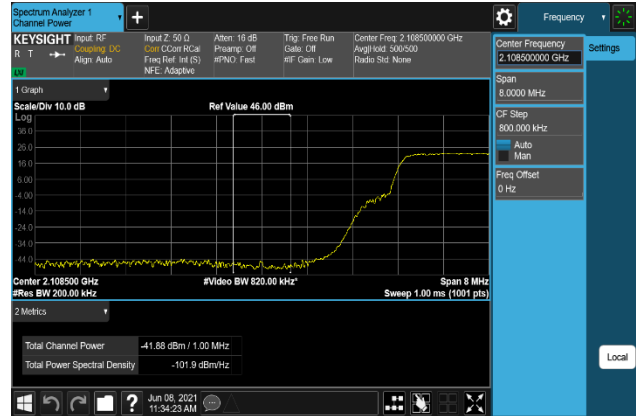


Plot 7-668. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_256QAM - Low Channel, Port 2)

FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
Test Report S/N: 8K21053101R1.A3L	Test Dates: 06/01/2021-06/15/2021	EUT Type: RRU(RF4402d)		Page 151 of 515



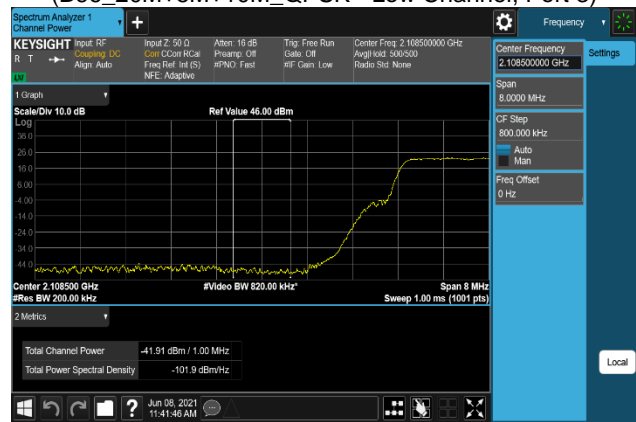
Plot 7-669. Band Edge Emission Plot
(B66_20M+5M+10M_QPSK - Low Channel, Port 3)



Plot 7-670. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_QPSK - Low Channel, Port 3)



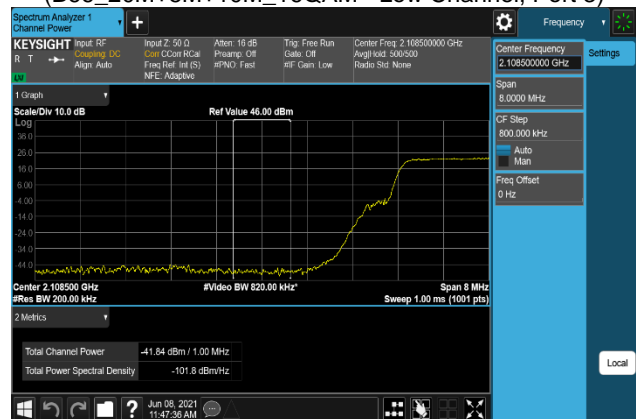
Plot 7-671. Band Edge Emission Plot
(B66_20M+5M+10M_16QAM - Low Channel, Port 3)



Plot 7-672. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_16QAM - Low Channel, Port 3)



Plot 7-673. Band Edge Emission Plot
(B66_20M+5M+10M_64QAM - Low Channel, Port 3)

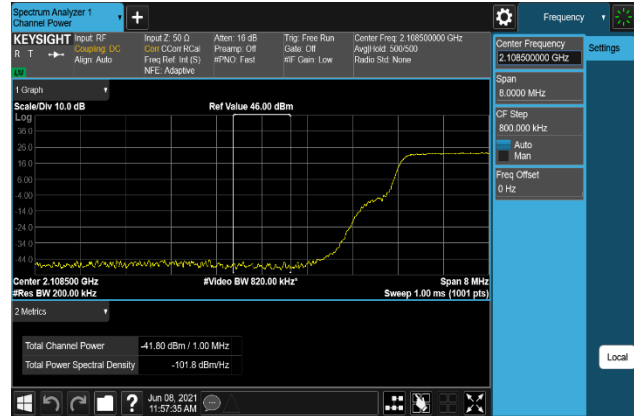


Plot 7-674. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_64QAM - Low Channel, Port 3)

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Test Report S/N: 8K21053101R1.A3L	Test Dates: 06/01/2021-06/15/2021	EUT Type: RRU(RF4402d)		Page 152 of 515



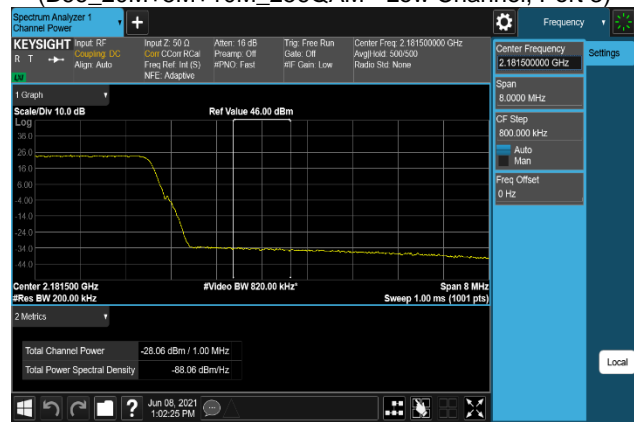
Plot 7-675. Band Edge Emission Plot
(B66_20M+5M+10M_256QAM - Low Channel, Port 3)



Plot 7-676. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_256QAM - Low Channel, Port 3)



Plot 7-677. Band Edge Emission Plot
(B66_20M+5M+10M_QPSK - High Channel, Port 0)



Plot 7-678. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_QPSK - High Channel, Port 0)



Plot 7-679. Band Edge Emission Plot
(B66_20M+5M+10M_16QAM - High Channel, Port 0)



Plot 7-680. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_16QAM - High Channel, Port 0)

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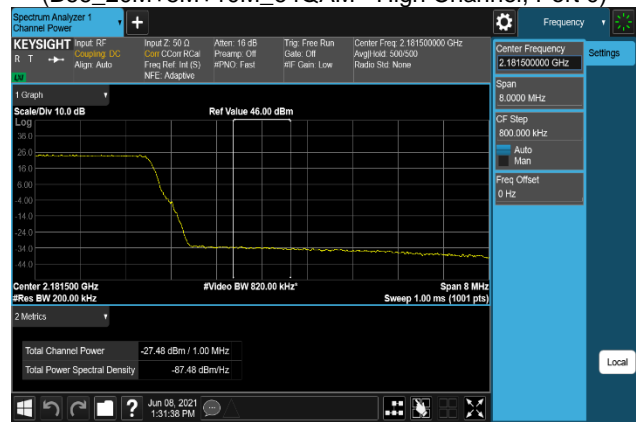
Plot 7-681. Band Edge Emission Plot
(B66_20M+5M+10M_64QAM - High Channel, Port 0)



Plot 7-682. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_64QAM - High Channel, Port 0)



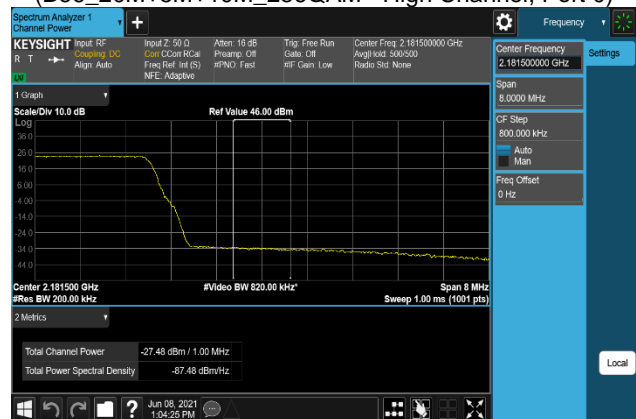
Plot 7-683. Band Edge Emission Plot
(B66_20M+5M+10M_256QAM - High Channel, Port 0)



Plot 7-684. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_256QAM - High Channel, Port 0)



Plot 7-685. Band Edge Emission Plot
(B66_20M+5M+10M_QPSK - High Channel, Port 1)



Plot 7-686. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_QPSK - High Channel, Port 1)

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Test Report S/N: 8K21053101R1.A3L	Test Dates: 06/01/2021-06/15/2021	EUT Type: RRU(RF4402d)		Page 154 of 515



Plot 7-687. Band Edge Emission Plot
(B66_20M+5M+10M_16QAM - High Channel, Port 1)



Plot 7-688. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_16QAM - High Channel, Port 1)



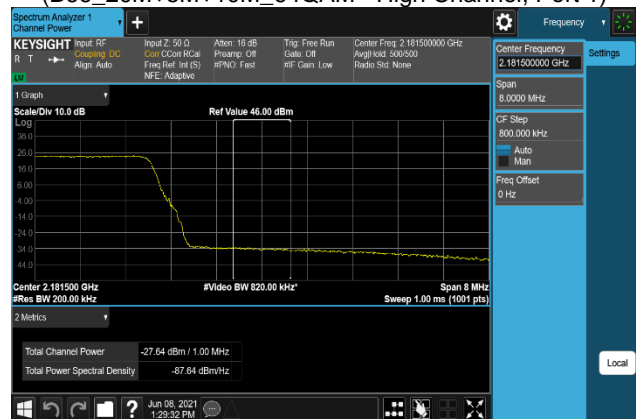
Plot 7-689. Band Edge Emission Plot
(B66_20M+5M+10M_64QAM - High Channel, Port 1)



Plot 7-690. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_64QAM - High Channel, Port 1)



Plot 7-691. Band Edge Emission Plot
(B66_20M+5M+10M_256QAM - High Channel, Port 1)



Plot 7-692. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_256QAM - High Channel, Port 1)

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Test Report S/N: 8K21053101R1.A3L	Test Dates: 06/01/2021-06/15/2021	EUT Type: RRU(RF4402d)		Page 155 of 515



Plot 7-693. Band Edge Emission Plot
(B66_20M+5M+10M_QPSK - High Channel, Port 2)



Plot 7-694. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_QPSK - High Channel, Port 2)



Plot 7-695. Band Edge Emission Plot
(B66_20M+5M+10M_16QAM - High Channel, Port 2)



Plot 7-696. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_16QAM - High Channel, Port 2)



Plot 7-697. Band Edge Emission Plot
(B66_20M+5M+10M_64QAM - High Channel, Port 2)



Plot 7-698. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_64QAM - High Channel, Port 2)

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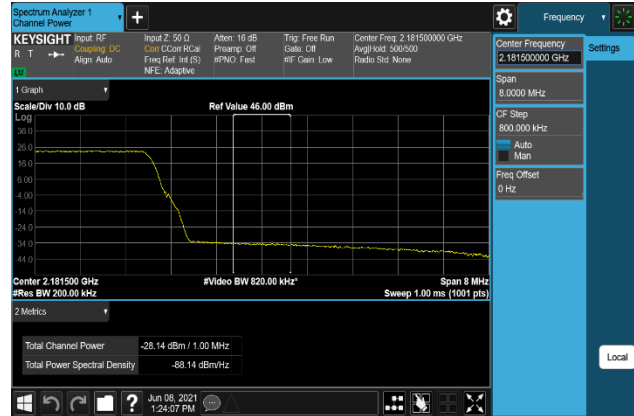
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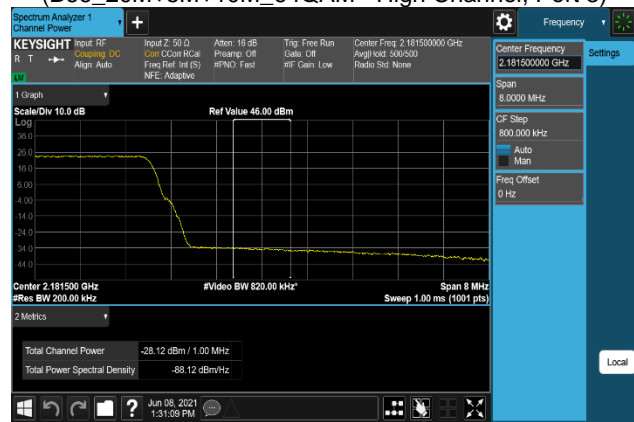
Plot 7-705. Band Edge Emission Plot
(B66_20M+5M+10M_64QAM - High Channel, Port 3)



Plot 7-707. Band Edge Emission Plot
(B66_20M+5M+10M_256QAM - High Channel, Port 3)



Plot 7-706. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_64QAM - High Channel, Port 3)



Plot 7-708. Band Edge Emission(Channel Power) Plot
(B66_20M+5M+10M_256QAM - High Channel, Port 3)

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